

Back-side Delivery Networks with Integrated Voltage Regulator

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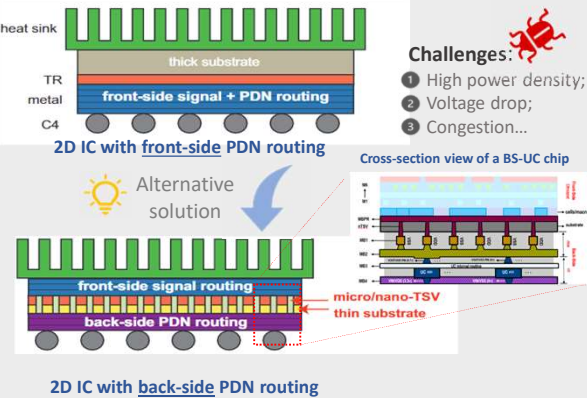
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Novel Computing Hierarchies



Motivations & Objectives

- Develop BS-PDN EDA flow;
- Address PDN challenges;
- Enable Back-side DC-DC unit converter (BS-UC) for BS-PDN.

An overview of FS- and BS-PDN

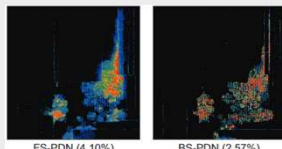


Recent Results

- Design implementation (Benchmark: OpenPiton)
 - ❖ BS-PDN → shorter wavelength (-14%)
 - less congestion.

	FS-PDN	BS-PDN	Δ (%)
Footprint (mm ²)	0.13	-	-
Metal stack	6M	6M+25MB	-
Rail pitch (CPP)	32	3	(-90.6%)
# Cells	317061	307123	(-3.1%)
Area Utilization (%)	71.17%	77.09%	(+8.3%)
WL (m)	1.52	1.30	(-14.5%)
PDN area (mm ²)	0.15	0.21	(+39.0%)
Freq (GHz)	0.97	1.06	(+9.2%)
Total power (mW)	92.4	85.9	(-7.0%)
Static IR drop (mV)	69.3	33.7	(-51.4%)

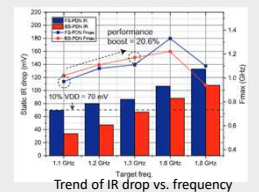
Routing wavelength distribution



Global routing congestion maps

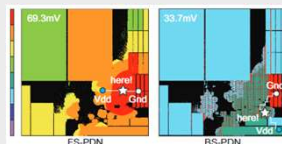
FS-PDN vs. BS-PDN

- PPA comparisons:
 - ❖ Timing improvement (+8.2%);
 - ❖ Power saving (-7.0%);
 - ❖ Cell area increase (+8.2%).
- Static IR drop analysis:
 - ❖ IR drop reduction (-51%);
 - ❖ Performance boost (20.6%).



Trend of IR drop vs. frequency

	FS-PDN	BS-PDN	Δ (%)
Internal (mW)	61.5	59.2	-3.7%
Switching (mW)	39.6	26.5	-33.4%
Leakage (mW)	0.3	0.3	-3.6%
Component			
Memory (mW)	36.5	35.4	-3.0%
Clock (mW)	13.4	12.5	-6.7%
Sequential (mW)	11.8	11.4	-3.4%
Combinational (mW)	30.8	26.5	-14.0%
Total (mW)	92.4	86.0	-6.9%



Static IR drop map

Power consumption breakdown



Technical Approach



- Technology setup: Based on in-house 3nm PDK.

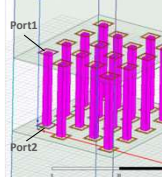
Metals				
	Group	Layer	Width (nm)	Resistivity (Ω/um)
back-side	MB	MB2-MB1	40	34
	BPR	MBPR	25	65
	Mx	M1-M3	12	347
front-side	My	M4-M5	18	101
	Mz	M6-M7	24	44

Vias				
	Size (um)	Pitch (um)	Resistance (Ohm)	KOZ (um)
micro-TSV	1.00	5.00	0.29	2 x 2
MB via	0.020	0.012	56.0	-
Mx via	0.012	0.024	63.5	-
My via	0.018	0.036	19.3	-
Mz via	0.024	0.048	10.8	-

Technology setup for 3nm PDK

- Design flow development:
 - ❖ Commercial tools and customized scripts;
 - ❖ Pattern-based PDN design;
 - ❖ Detailed IR-drop analysis, etc.

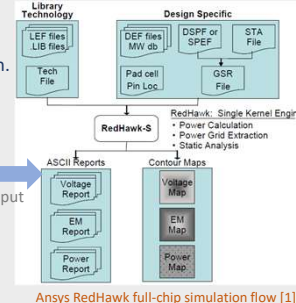
- TSV and BS-PDN modeling:
 - ❖ Based on Ansys HFSS and RedHawk;
 - ❖ Physical model → electrical model → tech file → full chip simulation.



TSV array model

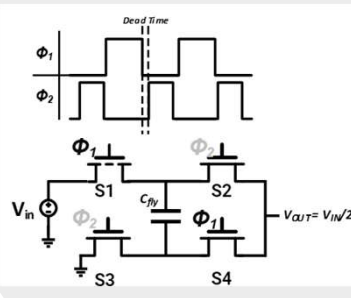
	nano-TSV	micro-TSV
Diameter (um)	0.06	1.0
KoZ width (um)	0.12	2.0
Pitch (um)	0.5	5.0
Length (um)	0.6	10.0
R (Ohm)	3.81	0.29
L (pH)	0.72	6.25
C (pF)	0.27	7.59

TSV lumped parasitics

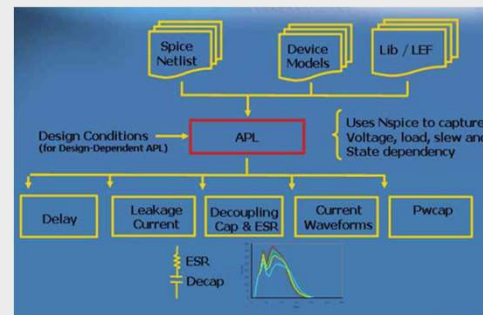


Ansys RedHawk full-chip simulation flow [1]

- BS-UC design and modeling:
 - ❖ Using SPICE simulation and cell characterization;
 - ❖ Key output: transient response, current switching behavior.

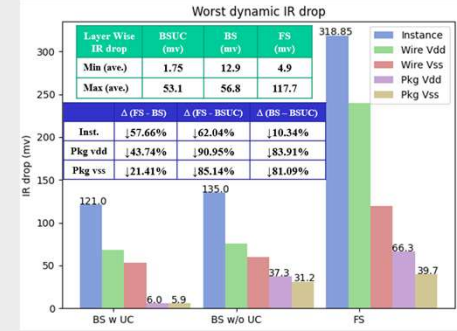


DC-DC converter circuit and schematic [5]



Characterization flow [1]

BS-UC benefits



- BS-UC can mitigate 10.34% worst instance IR-drop compared to backside without UC.
- BS-UC can mitigate more than 80% IR drop from pkg.
- BS-UC reduce the overall IR drop for all instance (min layer wise drop) because pkg IR drop propagates to every layer.

Comparison with the SOTA

Reference	Strength	Weakness
[2]	Enabled BS-PDN for a 2D commercial CPU design.	Have not considered impacts of BS-PDN on design PPA, have not included BS-UC.
[3]	Enabled BS-PDN for a 3D IC design.	
[4]	Enabled BS-PDN for both 2D and 3D ICs at A14 node.	
This study	Enabled BS-PDN, performed detailed PPA and IR drop analysis.	BS-UC is not yet included.

Key accomplishment



- Implemented an EDA flow for BS-PDN design & analysis:
 - ❖ Highly configurable;
 - ❖ BS-UC integration.
- Evaluated the benefits of BS-PDN and BS-UC in CPU design:
 - ❖ Routing congestion reduced;
 - ❖ Explainable performance and power improvements.
- Detailed IR drop analysis:
 - ❖ Identify the bottleneck for front-side power delivery;
 - ❖ DSE between performance and power integrity.

Reference

- [1] Ansys, "RedHawk User Manual", 2022.
- [2] Prasad, Divya, S. S. Teja Nibhanupudi, Shidhartha Das, Odysseas Zografos, Bilal Chehab, Satadru Sarkar, Rogier Baert, et al. "Buried Power Rails and Back-Side Power Grids: Arm® CPU Power Delivery Network Design Beyond 5nm." In 2019 IEEE International Electron Devices Meeting (IEDM), 19.1.1-19.1.4. San Francisco, CA, USA: IEEE, 2019. <https://doi.org/10.1109/IEDM419573.2019.8993617>.
- [3] Sisto, G., & Chehab, B. Gennere, R. Baert, R. Chen, P. Weckx, J. Ryckaert, et al. "IR-Drop Analysis of Hybrid Bonded 3D-ICs with Backside Power Delivery and μ-Amp; n-TSVs." In 2021 IEEE International Interconnect Technology Conference (IITC), 1-3, 2021. <https://doi.org/10.1109/IITC51362.2021.9537541>.
- [4] Chen, R., M. Lofrano, G. Mirabelli, G. Sisto, S. Yang, A. Jourdain, F. Schleicher, et al. "Power, Performance, Area and Thermal Analysis of 2D and 3D ICs at A14 Node Designed with Back-Side Power Delivery Network." In 2022 International Electron Devices Meeting (IEDM), 23.4.1-23.4.4, 2022. <https://doi.org/10.1109/IEDM45626.2022.10019149>.
- [5] Kwak, et al. A Reconfigurable Monolithic 3D Switched Capacitor DC-DC Converter with Back-End-of-Line Oxide Channel Transistor, MWSCAS, 2023.